

## Notice of References Cited

Application/Control No.  
10/023,920

Applicant(s)/Patent Under Reexam  
Tagge et al.

Examiner  
J. Pasterczyk

Art Unit  
1755

Page 1 of 1

### U.S. PATENT DOCUMENTS

	<b>Document Number</b> Country Code-Number-Kind Code	<b>Date</b> MM-YYYY <sup>1</sup>	<b>Name</b>	<b>Classification<sup>2</sup></b>	
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B	5,852,146	12/1998	Reichle et al.	526	172
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### NON-PATENT DOCUMENTS

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